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KATO ISAO**(54) **SYSTEM FOR TESTING SIGNAL PROCESSING
LSI**

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(57) Abstract

PURPOSE: To make it possible to perform a test by one testing terminal, by providing a testing selector in a signal processing LSI and connecting the same to an external demultiplexer and an external memory.

CONSTITUTION: A signal processing LSI2 is tested by selecting the parallel signal issued out from an objective digital signal processing block (DSP1)3 by a selector 9 operated in synchronous relation to an internal clock 8 and sending out said signal from a testing terminal C to accumulate the same in a memory 11 through an external demultiplexer 10. This operation is repeated a number of times corresponding to the number of signal bits. This accumulated memory content is converted by a D/A converter 12 to perform evaluation by a measuring device (M2)13. Therefore, only one terminal C may be used as the testing terminal and it is unnecessary to make a chip size large and the initial evaluation of planning is enabled and a planning time can be shortened.

